Electronic Supporting Information

Photoacid generator integrated terpolymer for electron beam lithography applications: sensitive resist with pattern transfer potential

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Experimental Section

Materials and methods

Acetonitrile and tetrahydrofuran (HPLC grade) were purchased from Merck, India and well dried before use. Tetramethyl ammonium hydroxide was purchased from Sigma Aldrich, India and used as received. FT-IR spectra were recorded on a Perkin Elmer Spectrum 2 spectrophotometer using KBr pellets. ¹H, ¹³C and ¹⁹F NMR spectra were recorded on Jeol JNM ECX 500 MHz spectrometer in DMSO-*d*₆. TGA measurements were performed on NETZSCH STA 449 F1 JUPITER Series instrument; the heating rate employed was 10 °C/min under N₂ atmosphere over a temperature range of 25-1000 °C. Molecular weight and polydispersity index (PDI) of GBLMA-MAMA-MAPDST was determined by performing gel permeation chromatography (GPC) analyses using PL gel mixed B 10 mm column on a 1260 Infinity Series instrument from Agilent. RAITH 150-Two was used as experimental tool for the electron beam lithography studies with 20 KV E.H.T. NanoMap-D stylus profilometer is used for the thickness measurements. FE-SEM Nova Nano SEM 450 FEI, Zeiss ultra 55 and Atomic Force Microscope (AFM) (Dimension Icon, Bruker) tools were used for imaging the critical dimensions of various patterns made on silicon substrates.

Synthesis and characterization of GBLMA-MAMA-MAPDST Resist

GBLMA,¹ MAMA² and MAPDST³ were synthesized according to the literature reports and characterized using spectroscopic techniques. GBLMA (0.3 gm, 1 eq), MAMA (1.15 gm, 2.8 eq), MAPDST (0.131 gm, 0.2 eq) and AIBN (0.023 gm, 0.08 eq, relative to all monomers) were dissolved in dry acetonitrile/tetrahydrofuran mixed solvents (1:2; V/V) under N₂

atmosphere. After that, resulting solution was filtered through 0.4 µm Teflon filters in a single armed polymerization flask which was equipped with rubber septum and magnetic stirring bar. After several freeze-pump- thaw cycles, the polymerization flask was placed in a preheated oil bath at 65 °C and allow the stirring in dark for 24 hours. After completion, the reaction mixture was poured into the petroleum ether and the resultant crude product was redissolved in minimum amount of methanol and re-precipitated in diethyl ether. The pure white solid of GBLMA-MAMA-MAPDST was filtered and dried over 50 °C for 12 h in a temperature controlled hot air oven. Yield: 0.650 gm. ¹H NMR (500 MHz, DMSO- d_6 , δ): 8.14 (brs, 2H, Ar H), 7.4 (brs, 2H, Ar H), 5.5 (brs, ¹H; CH, (cyclic GBLMA unit)), 4.33 (brd, 2H, CH₂, (cyclic GBLMA unit)), 3.27 (s, 6H; S(CH₃)₂), 2.4-1.0 (br peak, 3H, (Aliphatic CH₃ & CH₂ units); ¹³C NMR (125 MHz, DMSO-d₆) δ_{C} 176.17, 174.93, 172.67 (C=O), 153.87, 131.83, 129.62, 127.09, 125.15, 123.93, 122.96, 121.94, 119.39, 117.21(aromatic, CF₃), 86.63, 68.42, 65.15, 54.92, 46.93, 44.87 (CH₂), 37.59, 35.11, 33.86, 32.50, 28.73 (SCH₃), 28.68, 26.11, 21. 36, 15.0 (CH₃ aliphatic). ¹⁹F NMR (DMSO, 376 MHz, δ): -77.65 (3F, s, CF₃); IR (KBr): v = 2910 (CH₂), 1790-1719 (C=O), 1586.6, 1462.6, 1448.7 (C=C), 1380.8, 1257.3 (CF₃), 1220.6, 1148.1-1131.9 (C-O), 1029.8 (S=O), 954.7, 886.00, 842.0, 815.74, 756.10, 639.20, 573.9, 520.0.



Figure S1. Synthetic route of GBLMA-MAMA-MAPDST resist.



Figure S2. IR-profile of GBLMA-MAMA-MAPDST resist.



Figure S3. ¹H NMR of GBLMA-MAMA-MAPDST resist.



Figure S4. ¹³C NMR of GBLMA-MAMA-MAPDST resist.



Figure S5. ¹⁹F NMR of GBLMA-MAMA-MAPDST resist.



Figure S6. GPC data of GBLMA-MAMA-MAPDST resist.



Figure S7. TGA profile of GBLMA-MAMA-MAPDST polymer.



Figure S8. DSC profile of GBLMA-MAMA-MAPDST polymer.



Figure S9. Optical microscope image of GBLMA-MAMA-MAPDST resists coated on silicon substrate indicating uniform film formation.



Figure S10. Thickness measurements on GBLMA-MAMA-MAPDST polymer.



Figure S11. Thickness measurements of transferred line features on the silicon substrate at the etch time of 15 sec.



Figure S12. Thickness measurements of transferred line features on the silicon substrate at the etch time of 45 sec.

References

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